



Karlsruhe probe equipment and QA proposals/expertise

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Lab Expertise

Delphi: World largest 1996-2000 1.8m²



- Delphi:
 - Quality control on sensors and modules, Assembly of Pixel and Outer Barrel modules (Update '97)
- CDF II ISL:
 - Sensor Prototype evaluation
 - Quality control, Assembly fixture design and construction
- · CMS
 - Prototyping (sensor & modules)
 - Definition of QA procedure, Design of sensors
 - Material Analysis
 - Long term Testing
 - Irradiation
 - Definition of QA procedure for modules
 - Dedicated pinhole test, beam dump test, current/noise correlations ...
 - Bonding
 - Integration









Sensor Testing Equipment I



2 homemade flexible probe stations

- 6" (adaptable for larger size)
- cold chuck -10°C (+100°C to -10°C)
- very flexible
 - individual needles
 - bias travels with sensor
- switching matrix
- RH & T monitoring

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- LCR, electrometer, HV, quasistatic CV!
- Camera (incl. frame grabber)
- Double sided jig

Suitable for strip characterization of sensors and full modules





Sensor Testing Equipment II



Standard Measurements:

- Global:
 - IV, CV
- Strip:
 - Current, CaC, dielectric current (pinhole)
 - inter strip capacitance, inter strip resistance
- Special:
 - VFlat
 - Isurf

Software specialties:

- <u>All</u> parameters versus
 - Time
 - Voltage
 - Temperature
- Defined potential on neighbor pads
 - E.g. current measurement on DC while AC pad on voltage
- Current induced with IR
- Combination of all the above with different parameters; scriptable
- Applicable on full modules

















Longterm Station



- Long term testing
 - 10 sensors under bias voltage while logging current





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CMS process control (Florence, Strasbourg, Vienna)



- Special exhaustive set of measurements to monitor the processes
 - PQC EXTEND QTC + Redundancy done on dedicated teststructures:
 - Destructive tests
 - Full automatization allows a much higher sample
 - CV → V_FD
 - IV Breakdown voltage ,
 - Total leakage current
 - V_Flatband (On MOS structure)
 - Surface Current (On Gate Controlled Diode)
 - Cint in 10% from the parametrization
 - Interstrip resistance > 1 G Ω
 - Rpoly
 - P+ Implant Resistance: Rp+ < * kΩ/cm
 - Metal Layer resistance: Ral < * $m\Omega$ /square
 - Cac
 - Vbreak(ac) (destructive test)
 - Idiel @ higher voltages
- PQC results affect complete batch

CMS experience told us: THIS IS VERY IMPORTANT!



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Material Analysis with Environmental Electron microscope



Our neighbor institute runs an ESEM, which is accessible



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CMM and bonder



CMS module on our 50*50*50cm³ 3D CMM





Full automatic bonder





Proton irradiation





- Temperature < -10°C (nitrogen)
- Area: 20x40cm²
- Time for 15y LHC (100cm²):15min









Setup for surface irradiation only



60keV (~20keV photons) x-ray source

- @ 25mA ~148krad/h (on a spot ~2cm radius)
- Scanning possible
- Not suitable for LHC dose





Diagnose Test Station





Purpose: diagnostics of faulty modules Full CMS Readout LED array: (1050nm and 950nm) Movable LASER: for single strip/pitch scans (1050/650 nm)

- Possibility to set probe needles,
- Tests with a ⁹⁰Sr source
- Cosmics
- High resolution IV
- Possibility to introduce CV.
- Cold measurements possible with cold N







Fast Module Test for CMS

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- Test stands for CMS modules:
 - Full automatized readout
 - Readout warm and cold
 - Scenarios; scriptable
 - Cosmic trigger
 - LED array
 - Continous light
 - to artificially increase leakage current
 - Pulsed light
 - short illumination ~10 strips

Possible later adaptation for special SiLC tests after CMS production!









- Karlsruhe is well equipped and experienced to evaluate all new sensors and may agree later on to do quality assurance for SiLC
- We are looking forward to get sensors in hand
 - For Karlsruhe: We would "invest" one-two competent student(s) for the evaluations, BUT we then really need prototypes from the SiLC community

